

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	129	(257/328.ccls. or 257/168.ccls. or 257/327.ccls. or 257/329.ccls. or 257/135.ccls. or 257/339.ccls.) and (guard)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/04 13:24
L2	17	((semiconductor or die or chip or ic or (integrated adj circuit)) and (((guard near3 (rings or circles)) and (threshold or breakdown or break-down or (break near3 down))) same (number near3 (guard or rings)))) not ((semiconductor or die or chip or ic or (integrated adj circuit)) and (((guard near3 (rings or circles)) and (threshold or breakdown or break-down or (break near3 down))) same (equation or calculation or calculated))))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/04 13:44
L3	1461	(semiconductor or die or chip or ic or (integrated adj circuit)) and (guard near3 rings)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/04 13:45
S1	755	257/328.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/02 13:46
S2	977	(semiconductor or die or chip or ic or (integrated adj circuit)) and well and (guard near3 rings)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/02 13:48
S3	4	((semiconductor or die or chip or ic or (integrated adj circuit)) and well and (guard near3 rings)) and (break adj down adj voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/02 13:48
S4	264	((semiconductor or die or chip or ic or (integrated adj circuit)) and well and (guard near3 rings)) and (breakdown adj voltage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/02 13:48
S5	1363	(semiconductor or die or chip or ic or (integrated adj circuit)) and (guard near3 rings)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/04 13:45

S6	386	((semiconductor or die or chip or ic or (integrated adj circuit)) and (guard near3 rings)) not ((semiconductor or die or chip or ic or (integrated adj circuit)) and well and (guard near3 rings))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/02 14:14
S7	176	((semiconductor or die or chip or ic or (integrated adj circuit)) and (guard near3 rings)) and equation	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/02 14:15
S8	9	(semiconductor or die or chip or ic or (integrated adj circuit)) and (((guard near3 (rings or circles)) and (threshold or breakdown or break-down or (break near3 down))) same (equation or calculation or calculated))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/02 15:52
S9	23	(semiconductor or die or chip or ic or (integrated adj circuit)) and (((guard near3 (rings or circles)) and (threshold or breakdown or break-down or (break near3 down))) same (number near3 (guard or rings)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/02 15:53
S10	109	257/168.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/02 15:53
S11	507	257/327.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/02 15:53
S12	608	257/329.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/02 15:53
S13	115	257/135.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/02 15:53
S14	593	257/339.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/02 15:54

S15	2324	257/328.ccls. or 257/168.ccls. or 257/327.ccls. or 257/329.ccls. or 257/135.ccls. or 257/339.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/02 15:54
S16	113	(257/328.ccls. or 257/168.ccls. or 257/327.ccls. or 257/329.ccls. or 257/135.ccls. or 257/339.ccls.) and (guard)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/04 13:24
S17	17	((semiconductor or die or chip or ic or (integrated adj circuit)) and (((guard near3 (rings or circles)) and (threshold or breakdown or break-down or (break near3 down))) same (number near3 (guard or rings)))) not ((semiconductor or die or chip or ic or (integrated adj circuit)) and (((guard near3 (rings or circles)) and (threshold or breakdown or break-down or (break near3 down))) same (equation or calculation or calculated)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/04 13:44
S18	1	("4573066").PN.	USPAT; USOCR	OR	OFF	2004/09/02 16:11